

Search Notes

Application No.

10/765,533

Examiner

James P. Hughes

Applicant(s)

FINK ET AL.

Art Unit

2883

SEARCHED

Class	Subclass	Date	Examiner
250	492.3 493.1 494.1	8/3/04	J/K
	423R		
	423F 426		
445	50		
313	309		
	336		
	351		
	409		
	422		
	4195		
	497		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
(cold Adj. CATHODE) on (Field Adj. Emission) SANT- (Chindia on PASS64) WITH (electron on Beam or ebeam on e-beam) AND CLASSES	8/3/04	JH
(cold CATHODE) on (Field Adj. Emission)) SANT (Chindia) WITH (electron on Beam or ebeam on e-beam-)		
(cold Adj. CATHODE) LJK (Field Adj. Emission) ((hinder on PASS64)) NEAR2 (electron on Beam)		
(cold Adj. CATHODE) on (Field Adj. Emission) SANT- (Chindia on PASS64) WITH (electron on Beam or ebeam) (Hand Adj. beam) SANT- (electron Adj. Beam) on ebeam or e-beam) inversant closes		